

LCIE
Laboratoire de Moirans
Z.I. Centr'Alp
170, Rue de Chatagnon
38430 MOIRANS-FRANCE



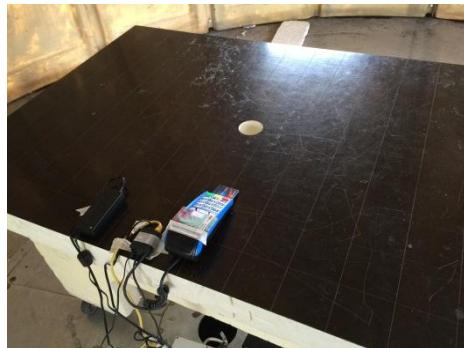
CONDUCTED AND RADIATED MEASUREMENT PHOTO

FCCID: XKB-ICT250V3
IC: 2586D-ICT250CLV3

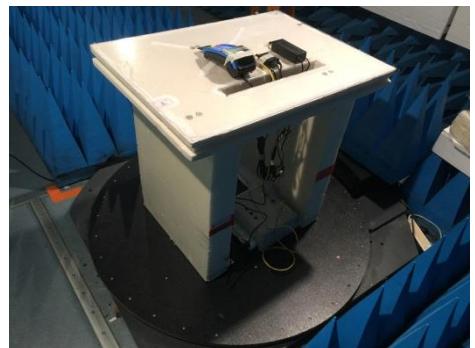
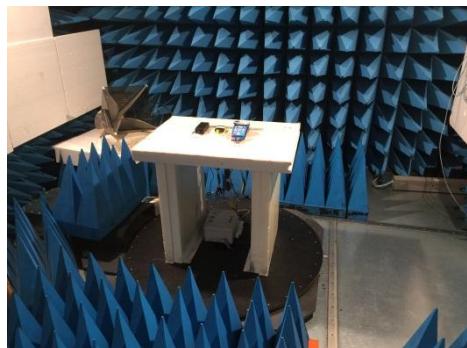
1.1 Conducted emission



1.2 Radiated emissions



Test setup on OATS



Test setup in anechoic chamber (9kHz to 1GHz)



Test setup in anechoic chamber (1GHz to 2GHz)